45 μV Offset, 0.4 μV/°C, Zero-Drift Operational Amplifier

NCS21871, NCV21871, NCS21872, NCV21872, NCS21874, NCV21874

The NCS21871, NCS21872 and NCS21874 family of zero-drift op amps feature offset voltage as low as 45 μV over the 1.8 V to 5.5 V supply voltage range. The zero-drift architecture reduces the offset drift to as low as 0.4 $\mu V/^{\circ}C$ and enables high precision measurements over both time and temperature. This family has low power consumption over a wide dynamic range and is available in space saving packages. These features make it well suited for signal conditioning circuits in portable, industrial, automotive, medical and consumer markets.

Features

• Gain-Bandwidth Product: 270 kHz to 350 kHz

• Low Supply Current: 17 μA (typ at 3.3 V)

• Low Offset Voltage: 45 μV max

• Low Offset Drift: $0.4 \mu V/^{\circ}C$ max

• Wide Supply Range: 1.8 V to 5.5 V

• Wide Temperature Range: -40°C to +125°C

• Rail-to-Rail Input and Output

• Available in Single, Dual and Quad Packages

 NCV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q100 Qualified and PPAP Capable

Applications

- Automotive
- Battery Powered/ Portable Application
- Sensor Signal Conditioning
- Low Voltage Current Sensing
- Filter Circuits
- Bridge Circuits
- Medical Instrumentation



ON Semiconductor®

www.onsemi.com



SOT23-5 SN SUFFIX CASE 483



SC70-5 SQ SUFFIX CASE 419A



UDFN8 MU SUFFIX CASE 517AW



MSOP-8 DM SUFFIX CASE 846A-02



SOIC-8 D SUFFIX CASE 751



SOIC-14 D SUFFIX CASE 751A



TSSOP-14 WB DT SUFFIX CASE 948G



FCT SUFFIX CASE 971BE

DEVICE MARKING INFORMATION

See general marking information in the device marking section on page 2 of this data sheet.

ORDERING INFORMATION

See detailed ordering and shipping information on page 3 of this data sheet.

DEVICE MARKING INFORMATION

Single Channel Configuration NCS21871, NCV21871



TSOP-5/SOT23-5 CASE 483



SC70-5 CASE 419A



ECP5 CASE 971BE

Dual Channel Configuration NCS21872, NCV21872



UDFN8, 2x2, 0.5P CASE 517AW

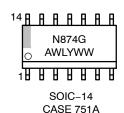


Micro8/MSOP8 CASE 846A-02



SOIC-8 CASE 751

Quad Channel Configuration NCS21874, NCV21874



N874 = Specific Device Code A = Assembly Location

Y = Year
W = Work Week
M = Date Code
G or = = Pb-Free Package

TSSOP-14 WB CASE 948G

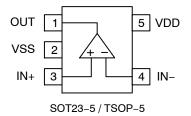
N874 = Specific Device Code A = Assembly Location

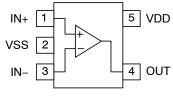
L = Wafer Lot
Y = Year
W = Work Week
= Pb-Free Package

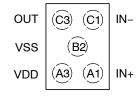
(Note: Microdot may be in either location)

PIN CONNECTIONS

Single Channel Configuration NCS21871, NCV21871



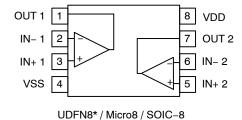




SC70-5 / SC-88-5 / SOT-353-5

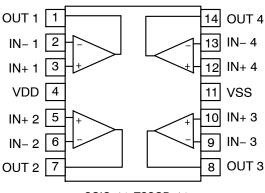
ECP5 (Top View)

Dual Channel Configuration NCS21872, NCV21872



^{*}The exposed pad of the UDFN8 package can be floated or connected to VSS.

Quad Channel Configuration NCS21874, NCV21874



SOIC-14, TSSOP-14

ORDERING INFORMATION

Temperature	Channels	Package	Device Part Number	Shipping [†]
COMMERCIAL AND IN	IDUSTRIAL			
-40°C to 125°C	Single	SOT23-5/TSOP-5	NCS21871SN2T1G	3000 / Tape & Reel
		SC70-5/SC-88-5/ SOT-353-5	NCS21871SQ3T2G	
		ECP5	NCS21871FCTTAG*	1
	Dual	MICRO-8	NCS21872DMR2G	4000 / Tape & Reel
		SOIC-8	NCS21872DR2G	3000 / Tape & Reel
		UDFN-8	NCS21872MUTBG*]
	Quad	SOIC-14	NCS21874DR2G	2500 / Tape & Reel
		TSSOP-14	NCS21874DTBR2G	
AUTOMOTIVE				
-40°C to 125°C	Single	SOT23-5/TSOP-5	NCV21871SN2T1G	3000 / Tape & Reel
		SC70-5/SC-88-5/ SOT-353-5	NCV21871SQ3T2G	
	Dual	MICRO-8	NCV21872DMR2G	4000 / Tape & Reel
		SOIC-8	NCV21872DR2G	3000 / Tape & Reel
	Quad	SOIC-14	NCV21874DR2G	2500 / Tape & Reel
		TSSOP-14	NCV21874DTBR2G	7

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

^{*}In Development. Contact local sales office for more information.

ABSOLUTE MAXIMUM RATINGS

Over operating free-air temperature, unless otherwise stated.

Parameter	Rating	Unit
Supply Voltage	6	V
INPUT AND OUTPUT PINS		
Input Voltage (Note 1)	(VSS) – 0.3 to (VDD) + 0.3	V
Input Current (Note 1)	±10	mA
Output Short Circuit Current (Note 2)	Continuous	
TEMPERATURE		
Operating Temperature Range	-40 to +125	°C
Storage Temperature Range	-65 to +150	°C
Junction Temperature	+150	°C
ESD RATINGS (Note 3)		
Human Body Model (HBM)	±4000	V
Charged Device Model (CDM)	±2000	V
OTHER RATINGS		
Latch-up Current (Note 4)	100	mA
MSL	Level 1	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Input terminals are diode-clamped to the power-supply rails. Input signals that can swing more than 0.3 V beyond the supply rails should be current limited to 10 mA or less
- 2. Short-circuit to ground.
- 3. This device series incorporates ESD protection and is tested by the following methods:
 - ESD Human Body Model tested per JEDEC standard JS-001 (AEC-Q100-002)
 - ESD Charged Device Model tested per JEDEC standard JESD22-C101 (AEC-Q100-011)
- 4. Latch-up Current tested per JEDEC standard: JESD78.

THERMAL INFORMATION (Note 5)

Parameter	Symbol	Package	Value	Unit
Thermal Resistance, Junction to Ambient	θ_{JA}	SOT23-5 / TSOP5	290	°C/W
Junction to Ambient		SC70-5 / SC-88-5 / SOT-353-5	290	
		ECP5	157	
		Micro8 / MSOP8	298	
		SOIC-8	250	
		UDFN8	228	
		SOIC-14	216	
		TSSOP-14	155	

As mounted on an 80x80x1.5 mm FR4 PCB with 650 mm² and 2 oz (0.07 mm) thick copper heat spreader. Following JEDEC JESD/EIA 51.1, 51.2, 51.3 test guidelines

RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol	Range	Unit
Supply Voltage (V _{DD} – V _{SS})	V _S	1.8 to 5.5	V
Specified Operating Temperature Range		-40 to 125	°C
Input Common Mode Voltage Range	V_{CM}	V _{SS} -0.1 to V _{DD} +0.1	V

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

ELECTRICAL CHARACTERISTICS: $V_S = 1.8 \text{ V to } 5.5 \text{ V}$ At $T_A = +25^{\circ}\text{C}$, $R_L = 10 \text{ k}\Omega$ connected to midsupply, $V_{CM} = V_{OUT} =$ midsupply, unless otherwise noted. **Boldface** limits apply over the specified operating temperature range, guaranteed by characterization and/or design.

Parameter	Symbol	Con	ditions	Min	Тур	Max	Unit
INPUT CHARACTERISTICS							
Offset Voltage	V _{OS}	V _S :	= +5 V		6	45	μV
Offset Voltage Drift vs Temp	$\Delta V_{OS}/\Delta T$	Vs	= 5 V		0.1	0.4	μV/°C
Offset Voltage Drift vs Supply	$\Delta V_{OS}/\Delta V_{S}$	T _A =	+25°C		0.4	8	μV/V
		Full tempe	erature range			12.6	-
Input Bias Current	I _{IB}	T _A =	+25°C		±60	±400	pА
(Note 6)		Full tempe	erature range		±400		-
Input Offset Current (Note 6)	l _{OS}	T _A =	+25°C		±50	±800	pА
Common Mode Rejection Ratio	CMRR	V _S =	= 1.8 V		111		dB
(Note 7)		V _S =	= 3.3 V		118		
		V _S =	= 5.0 V	102	123		
		V _S =	= 5.5 V		127		1
Input Capacitance	C _{IN}	Diffe	erential		4.1		pF
		Comm	on Mode		7.9		
OUTPUT CHARACTERISTICS	<u> </u>						
Open Loop Voltage Gain (Note 6)	A _{VOL}	V _{SS} + 100 mV <	V _O < V _{DD} – 100 mV	106	145		dB
Open Loop Output Impedance	Z _{out-OL}		See Figure 18		18	Ω	
Output Voltage High,	V _{OH}	T _A = +25°C			10	80	mV
Referenced to V _{DD}		Full temperature range				80	
Output Voltage Low,	V _{OL}	T _A = +25°C			10	80	mV
Referenced to V _{SS}		Full temperature range				80	
	I _O	Sinking Current			11		mA
		Sourcir	ng Current		5.0		
Capacitive Load Drive	C _L			S	ee Figure	14	
NOISE PERFORMANCE							
Voltage Noise Density	e _N	f _{IN} =	1 kHz		62		nV / √Hz
Voltage Noise	e _{P-P}	f _{IN} = 0.1	Hz to 10 Hz		1.1		μV_{PP}
		f _{IN} = 0.01	Hz to 1 Hz		0.5		
Current Noise Density	i _N	f _{IN} =	10 Hz		350		fA / √Hz
Channel Separation		NCS21872	2, NCS21874		135		dB
DYNAMIC PERFORMANCE							
Gain Bandwidth Product	GBWP	C _L = 100 pF	NCS21871, NCS21874		350		kHz
			NCS21872		270		
Gain Margin	A _M	C _L = 100 pF			18		dB
Phase Margin	ϕ м	C _L =	100 pF		55		0
Slew Rate	1	G = 1, V _{DD} = 5.5 V			1	1	
Slew Rate	SR	G = 1, V	_{DD} = 5.5 V		0.1		V/μs

- 6. Guaranteed by characterization and/or design
- 7. Specified over the full common mode range: V_{SS} 0.1 < V_{CM} < V_{DD} + 0.1
- 8. No load, per channel

ELECTRICAL CHARACTERISTICS: $V_S = 1.8 \text{ V to } 5.5 \text{ V}$ At $T_A = +25^{\circ}\text{C}$, $R_L = 10 \text{ k}\Omega$ connected to midsupply, $V_{CM} = V_{OUT} =$ midsupply, unless otherwise noted. **Boldface** limits apply over the specified operating temperature range, guaranteed by characterization and/or design.

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
POWER SUPPLY						
Power Supply Rejection Ratio	PSRR	$T_A = +25^{\circ}C$	106	130		dB
		Full temperature range	98			
Turn-on Time	t _{ON}	V _S = 5 V		100		μs
Quiescent Current	IQ	$1.8 \text{ V} \le \text{V}_{\text{S}} \le 3.3 \text{ V}$		20	40	μΑ
(Note 8)					40	
		$3.3 \text{ V} < \text{V}_{\text{S}} \le 5.5 \text{ V}$		28	45	
					45	

- 6. Guaranteed by characterization and/or design
- 7. Specified over the full common mode range: V_{SS} 0.1 < V_{CM} < V_{DD} + 0.1
- 8. No load, per channel

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL CHARACTERISTICS

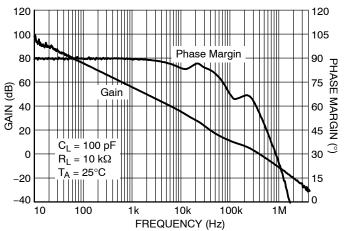


Figure 1. Open Loop Gain and Phase Margin vs. Frequency

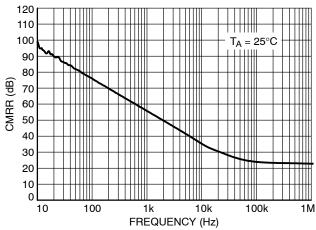


Figure 2. CMRR vs. Frequency

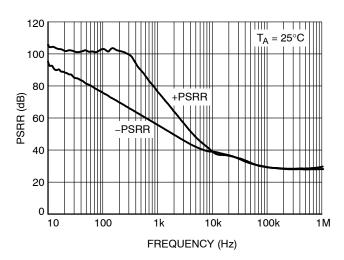


Figure 3. PSRR vs. Frequency

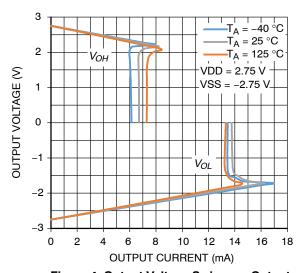


Figure 4. Output Voltage Swing vs. Output Current at $V_S = 5.5 \text{ V}$

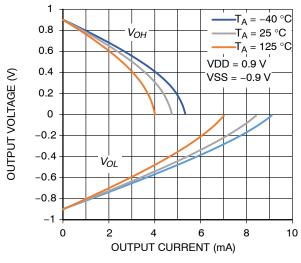


Figure 5. Output Voltage Swing vs. Output Current at $V_S = 1.8 \text{ V}$

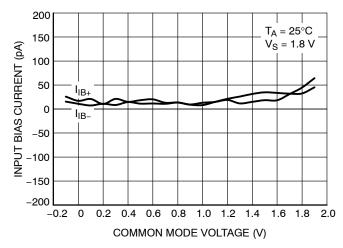
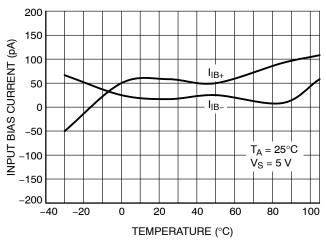


Figure 6. Input Bias Current vs. Common Mode Voltage

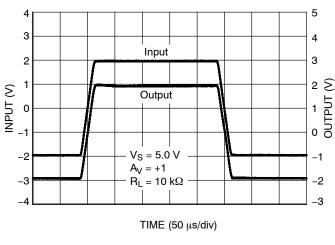
TYPICAL CHARACTERISTICS



30 $V_S = 5.5 V$ 25 $V_S = 5.0 V$ V_S = 3.3 V 20 la (MA) 15 $V_{S} = 1.8 V$ 10 5 Per Channel 0 20 40 -40-20 60 80 100 TEMPERATURE (°C)

Figure 7. Input Bias Current vs. Temperature

Figure 8. Quiescent Current vs. Temperature



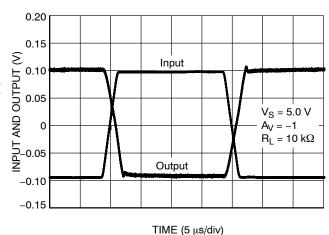


Figure 9. Large Signal Step Response

Figure 10. Small Signal Step Response

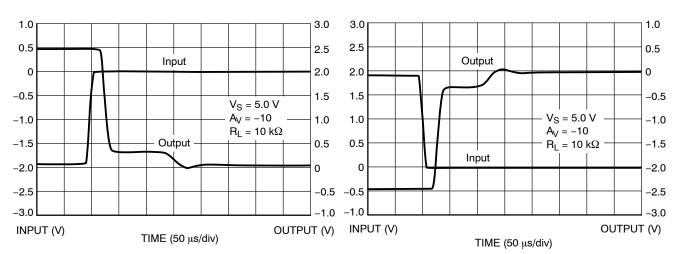


Figure 11. Positive Overvoltage Recovery

Figure 12. Negative Overvoltage Recovery

TYPICAL CHARACTERISTICS

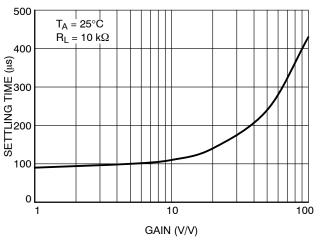


Figure 13. Setting Time to 0.1% vs. Closed-Loop Gain

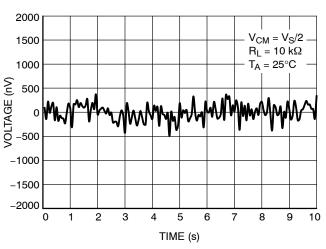


Figure 15. 0.1 Hz to 10 Hz Noise

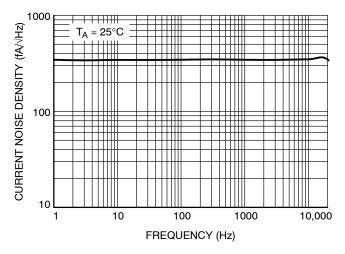


Figure 17. Current Noise Density vs. Frequency

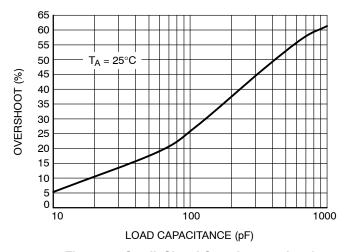


Figure 14. Small-Signal Overshoot vs. Load Capacitance

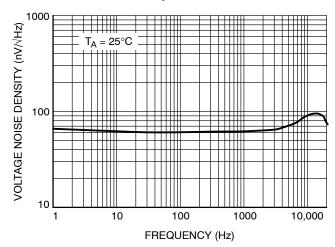


Figure 16. Voltage Noise Density vs. Frequency

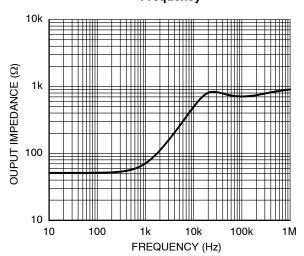


Figure 18. Open Loop Output Impedance vs. Frequency

APPLICATIONS INFORMATION

OVERVIEW

The NCS21871, NCS21872, and NCS21874 precision op amps provide low offset voltage and zero drift over temperature. The input common mode voltage range extends 100 mV beyond the supply rails to allow for sensing near ground or VDD. These features make the NCS21871 series well–suited for applications where precision is required, such as current sensing and interfacing with sensors.

The NCS21871 series of precision op amps uses a chopper-stabilized architecture, which provides the advantage of minimizing offset voltage drift over temperature and time. The simplified block diagram is shown in Figure 19. Unlike the classical chopper architecture, the chopper stabilized architecture has two signal paths.

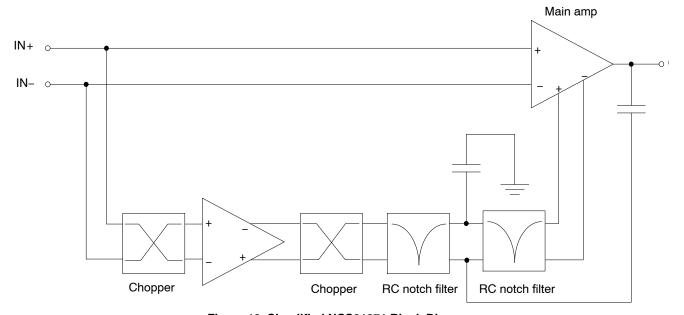


Figure 19. Simplified NCS21871 Block Diagram

In Figure 19, the lower signal path is where the chopper samples the input offset voltage, which is then used to correct the offset at the output. The offset correction occurs at a frequency of 125 kHz. The chopper-stabilized architecture is optimized for best performance at frequencies up to the related Nyquist frequency (1/2 of the offset correction frequency). As the signal frequency exceeds the Nyquist frequency, 62.5 kHz, aliasing may occur at the output. This is an inherent limitation of all chopper and chopper-stabilized architectures. Nevertheless, the NCS21871 op amps have minimal aliasing up to 125 kHz and low aliasing up to 190 kHz when compared to competitor parts from other manufacturers. ON Semiconductor's patented approach utilizes two

cascaded, symmetrical, RC notch filters tuned to the chopper frequency and its fifth harmonic to reduce aliasing effects.

The chopper–stabilized architecture also benefits from the feed–forward path, which is shown as the upper signal path of the block diagram in Figure 19. This is the high speed signal path that extends the gain bandwidth up to 350 kHz. Not only does this help retain high frequency components of the input signal, but it also improves the loop gain at low frequencies. This is especially useful for low–side current sensing and sensor interface applications where the signal is low frequency and the differential voltage is relatively small.

APPLICATION CIRCUITS

Low-Side Current Sensing

Low-side current sensing is used to monitor the current through a load. This method can be used to detect over-current conditions and is often used in feedback control, as shown in Figure 20. A sense resistor is placed in series with the load to ground. Typically, the value of the

sense resistor is less than 100 m Ω to reduce power loss across the resistor. The op amp amplifies the voltage drop across the sense resistor with a gain set by external resistors R1, R2, R3, and R4 (where R1 = R2, R3 = R4). Precision resistors are required for high accuracy, and the gain is set to utilize the full scale of the ADC for the highest resolution.

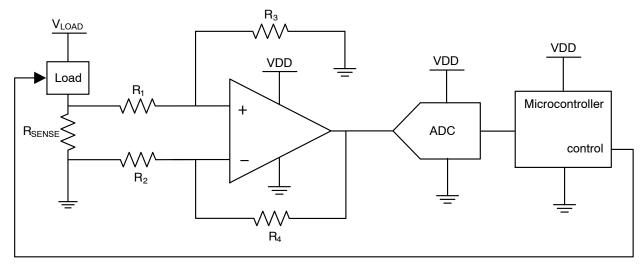


Figure 20. Low-Side Current Sensing

Differential Amplifier for Bridged Circuits

Sensors to measure strain, pressure, and temperature are often configured in a Wheatstone bridge circuit as shown in Figure 21. In the measurement, the voltage change that is

produced is relatively small and needs to be amplified before going into an ADC. Precision amplifiers are recommended in these types of applications due to their high gain, low noise, and low offset voltage.

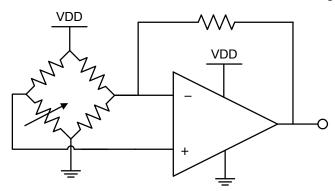


Figure 21. Bridge Circuit Amplification

EMI Susceptibility and Input Filtering

Op amps have varying amounts of EMI susceptibility. Semiconductor junctions can pick up and rectify EMI signals, creating an EMI-induced voltage offset at the output, adding another component to the total error. Input pins are the most sensitive to EMI. The NCS21871 op amp family integrates low-pass filters to decrease sensitivity to EMI.

General Layout Guidelines

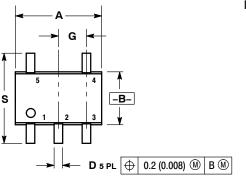
To ensure optimum device performance, it is important to follow good PCB design practices. Place $0.1~\mu F$ decoupling capacitors as close as possible to the supply pins. Keep traces short, utilize a ground plane, choose surface–mount components, and place components as close as possible to the device pins. These techniques will reduce susceptibility to electromagnetic interference (EMI). Thermoelectric effects can create an additional temperature dependent offset voltage at the input pins. To reduce these effects, use metals with low thermoelectric–coefficients and prevent temperature gradients from heat sources or cooling fans.

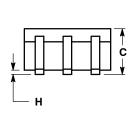
UDFN8 Package Guidelines

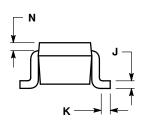
The UDFN8 package has an exposed leadframe die pad on the underside of the package. This pad should be soldered to the PCB, as shown in the recommended soldering footprint in the Package Dimensions section of this datasheet. The center pad can be electrically connected to VSS or it may be left floating. When connected to VSS, the center pad acts as a heat sink, improving the thermal resistance of the part.

PACKAGE DIMENSIONS

SC-88A (SC-70-5/SOT-353) CASE 419A-02 ISSUE L



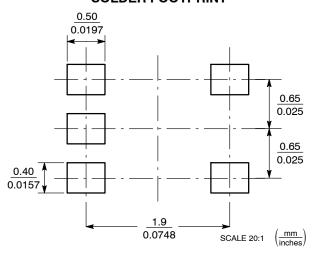




- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: INCH.
 3. 419A-01 OBSOLETE. NEW STANDARD 419A-02.
 4. DIMENSIONS A AND B DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BLIBES BURRS.

	INCHES		MILLIMETERS	
DIM	MIN	MAX	MIN	MAX
Α	0.071	0.087	1.80	2.20
В	0.045	0.053	1.15	1.35
C	0.031	0.043	0.80	1.10
D	0.004	0.012	0.10	0.30
G	0.026	BSC	0.65 BSC	
Н		0.004		0.10
J	0.004	0.010	0.10	0.25
K	0.004	0.012	0.10	0.30
N	0.008 REF		0.20	REF
S	0.079	0.087	2.00	2.20

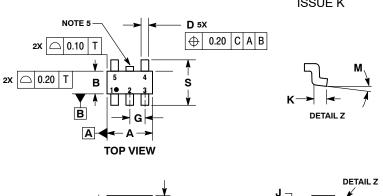
SOLDER FOOTPRINT

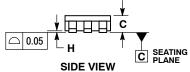


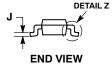
*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

TSOP-5 CASE 483-02 ISSUE K







NOTES:

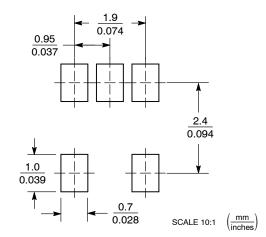
- 1. DIMENSIONING AND TOLERANCING PER ASME
- Y14.5M, 1994.
 2. CONTROLLING DIMENSION: MILLIMETERS.
 3. MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH THICKNESS. MINIMUM LEAD THICKNESS IS THE
- MINIMUM THICKNESS OF BASE MATERIAL.

 4. DIMENSIONS A AND B DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.15 PER SIDE. DIMENSION A.

 5. OPTIONAL CONSTRUCTION: AN ADDITIONAL
- TRIMMED LEAD IS ALLOWED IN THIS LOCATION.
 TRIMMED LEAD NOT TO EXTEND MORE THAN 0.2

	MILLIMETERS				
DIM	MIN MAX				
Α	3.00	BSC			
В	1.50	BSC			
C	0.90	1.10			
D	0.25	0.50			
G	0.95	BSC			
Н	0.01	0.10			
7	0.10	0.26			
K	0.20	0.60			
М	0 °	10°			
s	2.50	3.00			

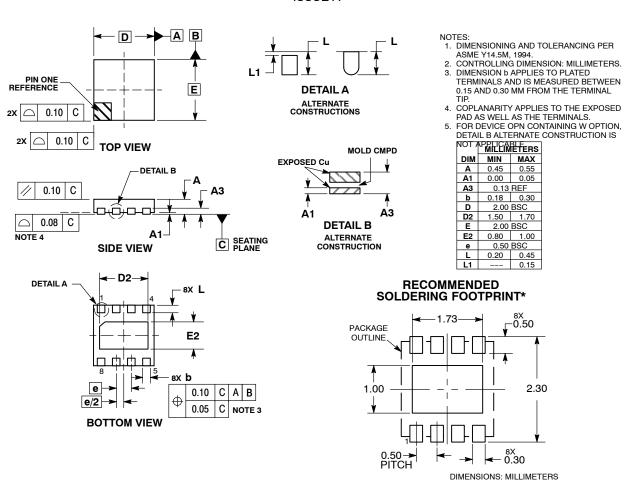
SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

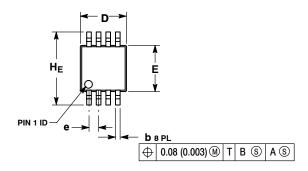
UDFN8, 2x2 CASE 517AW ISSUE A

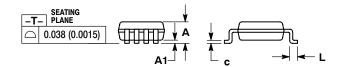


^{*}For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

Micro8™ CASE 846A-02 **ISSUE J**





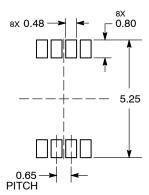
- NOTES: 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: MILLIMETER.
 DIMENSION A DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRIS MOLD FLASH, PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE.

 DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER SIDE.

5	8464-01	OBSOLETE.	NEW STANDARD	8464-02

	MILLIMETERS			INCHES		
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α	-		1.10			0.043
A1	0.05	0.08	0.15	0.002	0.003	0.006
b	0.25	0.33	0.40	0.010	0.013	0.016
С	0.13	0.18	0.23	0.005	0.007	0.009
D	2.90	3.00	3.10	0.114	0.118	0.122
E	2.90	3.00	3.10	0.114	0.118	0.122
е	0.65 BSC				0.026 BSC	
L	0.40	0.55	0.70	0.016	0.021	0.028
HE	4.75	4.90	5.05	0.187	0.193	0.199

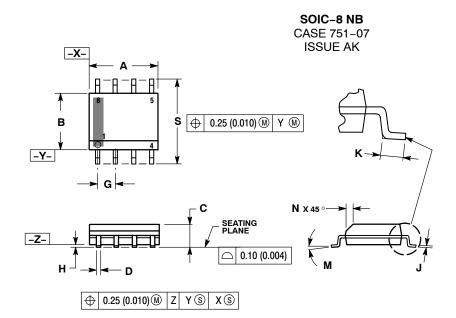
RECOMMENDED SOLDERING FOOTPRINT*



DIMENSION: MILLIMETERS

^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS



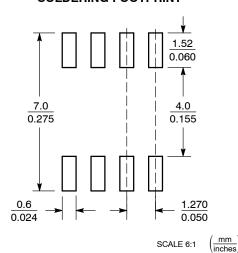
NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: MILLIMETER.

- CONTROLLING DIMENSION: MILLIMETER.
 DIMENSION A AND B DO NOT INCLUDE
 MOLD PROTRUSION.
 MAXIMUM MOLD PROTRUSION 0.15 (0.006)
 PER SIDE.
 DIMENSION D DOES NOT INCLUDE DAMBAR
 PROTRUSION SHALL BE 0.127 (0.005) TOTAL
 IN EXCESS OF THE D DIMENSION AT
 MAXIMUM MATERIAL CONDITION
- MAXIMUM MATERIAL CONDITION.
 6. 751–01 THRU 751–06 ARE OBSOLETE. NEW STANDARD IS 751–07.

	MILLIMETERS		S INCHES	
DIM	MIN	MAX	MIN	MAX
Α	4.80	5.00	0.189	0.197
В	3.80	4.00	0.150	0.157
С	1.35	1.75	0.053	0.069
D	0.33	0.51	0.013	0.020
G	1.27	7 BSC	0.050 BSC	
Н	0.10	0.25	0.004	0.010
7	0.19	0.25	0.007	0.010
K	0.40	1.27	0.016	0.050
M	0 °	8 °	0 °	8 °
N	0.25	0.50	0.010	0.020
S	5.80	6.20	0.228	0.244

SOLDERING FOOTPRINT*

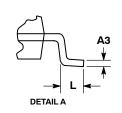


*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

В Н 13X **b** | 🕁 | 0.25 (M) | B (M) 0.25 M C A S $\overline{\Phi}$



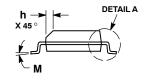


NOTES:

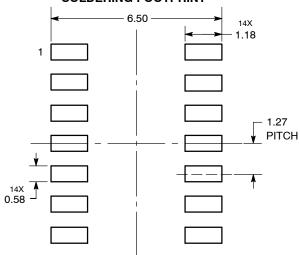
- 1. DIMENSIONING AND TOLERANCING PER
- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
 CONTROLLING DIMENSION: MILLIMETERS.
 DIMENSION b DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.13 TOTAL IN EXCESS OF AT MAXIMUM MATERIAL CONDITION.
 DIMENSIONS D AND E DO NOT INCLUDE MOLD PROTRUSIONS.
- 5. MAXIMUM MOLD PROTRUSION 0.15 PER

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
Α	1.35	1.75	0.054	0.068
A1	0.10	0.25	0.004	0.010
А3	0.19	0.25	0.008	0.010
b	0.35	0.49	0.014	0.019
D	8.55	8.75	0.337	0.344
Е	3.80	4.00	0.150	0.157
e	1.27	BSC	0.050 BSC	
Н	5.80	6.20	0.228	0.244
h	0.25	0.50	0.010	0.019
L	0.40	1.25	0.016	0.049
М	0°	7°	0°	7°





SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

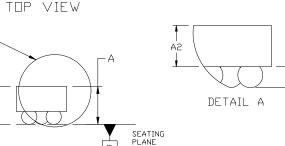
ECP5, 1.116x0.822x0.58 CASE 971BE ISSUE O

NDTES:

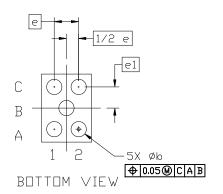
- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS

Α1

- 3. DATUM C, THE SEATING PLANE, IS DEFINED BY THE SPERICAL CROWNS OF THE CONTACT BALLS.
- 4. COPLANARITY APPLIES TO THE SPHERICAL CROWNS
 OF THE CONTACT BALLS.
- 5. DIMENSION 6 IS MEASURED AT THE MAXIMUM CONTACT BALL DIAMETER PARALLEL TO DATUM C.



	MILLIMETERS			
DIM	MIN.	N□M.	MAX.	
Α	0.535	0.580	0.625	
A1	0.175	0.195	0.215	
A2	0.360	0.385	0.410	
b	0.25	0.27	0.29	
D	1.086	1.116	1.146	
E	0.792	0.822	0.852	
е	0.40 BSC			
e1	0.3465 BSC			



SIDE VIEW

– E **⊸**

PIN 1 REFERENCE

DETAIL A

// 0.10 C

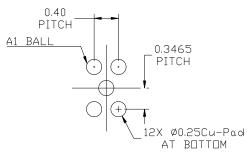
0.05 C

Α

В

D

С

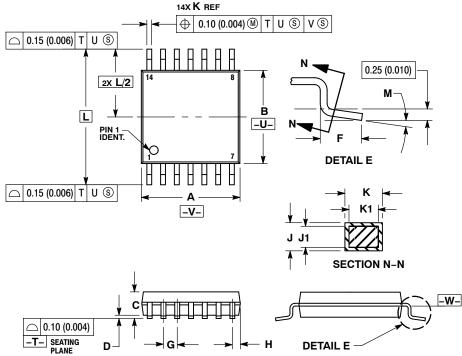


RECOMMENDED MOUNTING FOOTPRINT* (NSMD PAD TYPE)

* For additional information on our Pb-Free strategy and soldering details, please download the DN Semiconductor Soldering and Mounting Techniques Reference Manual, SDLDERRM/D.

PACKAGE DIMENSIONS

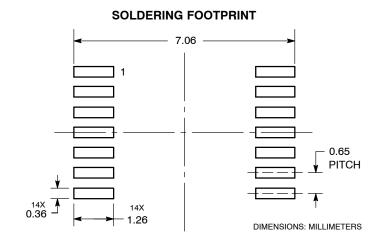
TSSOP-14 WB CASE 948G ISSUE C



NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. CONTROLLING DIMENSION: MILLIMETER.
- 3. DIMENSION A DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS.
- HLASH, PHOTHUSIONS OH GATE BUHRS.
 MOLD FLASH OR GATE BURRS SHALL NOT
 EXCEED 0.15 (0.006) PER SIDE.
 4. DIMENSION B DOES NOT INCLUDE
 INTERLEAD FLASH OR PROTRUSION.
 INTERLEAD FLASH OR PROTRUSION SHALL
 NOT EXCEED 0.25 (0.010) PER SIDE.
 5. DIMENSION K DOES NOT INCLUDE DAMBAR
 PROTRUSION. ALLOWABLE DAMBAR
 PROTRUSION. ALLOWABLE DAMBAR
- PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE K DIMENSION AT MAXIMUM MATERIAL CONDITION.
- TERMINAL NUMBERS ARE SHOWN FOR REFERENCE ONLY.
- DIMENSION A AND B ARE TO BE
 DETERMINED AT DATUM PLANE -W-.

	MILLIN	IETERS	INCHES	
DIM	MIN	MAX	MIN	MAX
Α	4.90	5.10	0.193	0.200
В	4.30	4.50	0.169	0.177
С		1.20		0.047
D	0.05	0.15	0.002	0.006
F	0.50	0.75	0.020	0.030
G	0.65 BSC		0.026 BSC	
Н	0.50	0.60	0.020	0.024
J	0.09	0.20	0.004	0.008
J1	0.09	0.16	0.004	0.006
Κ	0.19	0.30	0.007	0.012
K1	0.19	0.25	0.007	0.010
٦	6.40 BSC		0.252 BSC	
М	0 °	8 °	0 °	8 °



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